

12 **EUROPEAN PATENT APPLICATION**

21 Application number: **87113138.9**

51 Int. Cl.4: **G11C 29/00**

22 Date of filing: **08.09.87**

30 Priority: **08.09.86 JP 210996/86**
08.09.86 JP 210997/86

43 Date of publication of application:
13.04.88 Bulletin 88/15

64 Designated Contracting States:
DE FR GB

88 Date of deferred publication of the search report:
26.04.89 Bulletin 89/17

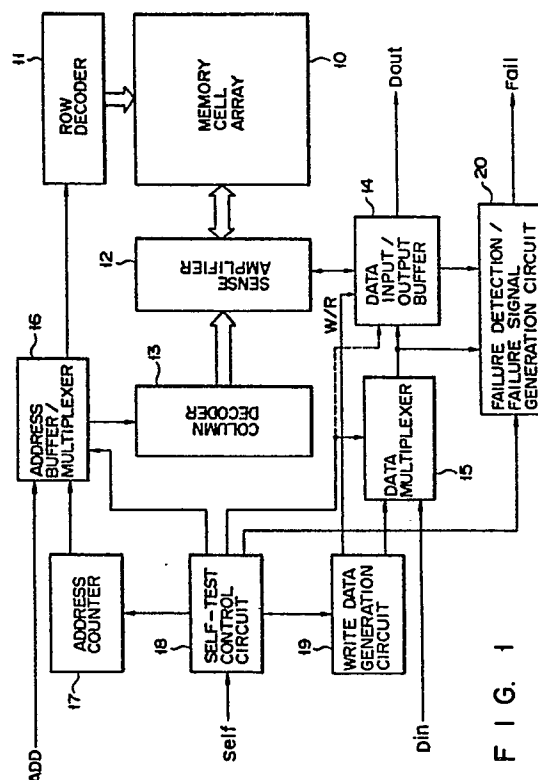
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54 **Semiconductor memory device with a self-testing function.**

57 A semiconductor memory device comprises a self-test circuit (17, 18, 19, 20). The self-test circuit starts to operate in response to a control signal. The self-test circuit controls the operation of data writing and data reading so that data are written into the memory cells in the memory cell array and read out the data from the memory cells. The self-test circuit checks whether or not an error is contained in the read data by comparing the read data with the write data.



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EP 87 11 3138

DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int. Cl.4)
Y	PATENT ABSTRACTS OF JAPAN, vol. 6, no. 62 (P-111)[940], 21st April 1982; & JP-A-57 3299 (NIPPON DENKI K.K.) 08-01-1982 * Abstract *	1-3,5-13	G 11 C 29/00
Y	WO-A-8 601 036 (HUGHES AIRCRAFT) * Abstract; claims 25,28,30,31; page 23, lines 7-29; figure 10a; page 24, lines 10-19 *	1-3,5-13	
Y	EP-A-0 127 015 (SIEMENS) * Abstract *	6	
Y	IBM TECHNICAL DISCLOSURE BULLETIN, vol. 19, no. 9, February 1977, pages 3487-3488, New York, US; J.N. ARNOLD et al.: "Pattern generator for a multipart number test system" * Page 3487 *	3	
Y	EP-A-0 104 442 (SIEMENS) * Abstract; page 2, lines 14-28; page 4, lines 30-36 *	11,12	TECHNICAL FIELDS SEARCHED (Int. Cl.4)
A		14-16	G 11 C G 06 F
A	PATENT ABSTRACTS OF JAPAN, vol. 6, no. 13 (P-99)[891], 26th January 1982; & JP-A-56 137 583 (FUJITSU K.K.) 27-10-1981 * Whole document *	4	
A	EP-A-0 092 245 (MOSTEK) * Page 5; page 9, lines 12-21; figure 3 *	14-16	
The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 07-02-1989	Examiner COHEN B.
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document			